

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/028,629 | | Applicant(s)/Patent Under Reexamination CHAPMAN ET AL. | |
| | Examiner Toan M Le | | Art Unit 2863 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------|----------------|
| X | A | US-6389360 | 05-2002 | Alft et al. | 702/9 |
| X | B | US-6025851 | 02-2000 | Valdes et al. | 345/442 |
| X | C | US-6441823 | 08-2002 | Ananya | 345/442 |
| X | D | US-6111588 | 08-2000 | Newell | 345/442 |
| X | E | US-5821414 | 10-1998 | Noy et al. | 73/152.54 |
| X | F | US-6523623 | 02-2003 | Schuh | 175/45 |
| X | G | US-6577954 | 06-2003 | Alft et al. | 702/9 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| X | U | "Derivation of a standard set of geometric constraints for parametric modeling and data exchange", Bettig et al., Computer-Aided Design 33 (2001) 17-33 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.